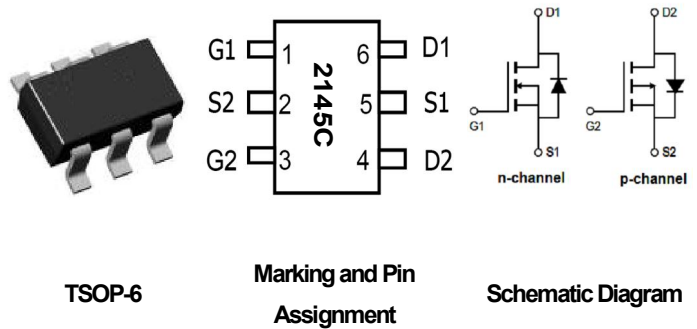


Main Product Characteristics

| | N-Ch | P-Ch |
|--------------------|--------|--------|
| V_{DSS} | 20V | -20V |
| $R_{DS(on)}(typ.)$ | 38mohm | 64mohm |
| I_D | 4.8A | 2.9A |



Features and Benefits

- Advanced trench MOSFET process technology
- Special designed for load switching and battery protection applications
- 150°C operating temperature
- Lead free product



Description

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in load switching and a wide variety of other applications.

Absolute Max Rating

| Symbol | Parameter | Max. | | Units |
|--------------------------|--|--------------|--------------|------------|
| | | N-channel | P-channel | |
| $I_D @ TC = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V$ ① | 4.8 | -2.9 | A |
| $I_D @ TC = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V$ ① | 3.9 | -2.4 | |
| I_{DM} | Pulsed Drain Current② | 17 | -11 | |
| $P_D @ TC = 25^\circ C$ | Power Dissipation③ | 1.7 | 1.7 | W |
| V_{DS} | Drain-Source Voltage | 20 | -20 | V |
| V_{GS} | Gate-to-Source Voltage | ± 8 | ± 8 | V |
| T_J T_{STG} | Operating Junction and Storage Temperature Range | -55 to + 150 | -55 to + 150 | $^\circ C$ |

Thermal Resistance

| Symbol | Characteristics | Typ. | Max. | | Units |
|--------|--|------|-----------|-----------|--------------|
| | | | N-channel | P-channel | |
| | Junction-to-ambient ($t \leq 10s$) ④ | — | 76 | 114 | $^\circ C/W$ |



SSF2145CH6

20V Complementary MOSFET

| | | | | | |
|--|---|---|----|----|------|
| | Junction-to-Ambient (PCB mounted, steady-state) ④ | — | 53 | 53 | °C/W |
|--|---|---|----|----|------|

Electrical Characteristics @T_A=25°C unless otherwise specified

| Symbol | Parameter | | Min. | Typ. | Max. | Units | Conditions |
|----------------------|--------------------------------------|-----------|------|-------|------|-------|--|
| V _{(BR)DSS} | Drain-to-Source breakdown voltage | N-channel | 20 | — | — | V | V _{GS} = 0V, I _D = 250μA |
| | | | 22 | — | — | | T _J = 125°C |
| | | P-channel | -20 | — | — | | V _{GS} = 0V, I _D = -250μA |
| | | | -22 | — | — | | T _J = 125°C |
| R _{DS(on)} | Static Drain-to-Source on-resistance | N-channel | — | 38 | 55 | mΩ | V _{GS} =4.5V, I _D = 3.6A |
| | | P-channel | — | 68 | 80 | | V _{GS} =-4.5V, I _D = -3A |
| | | N-channel | — | 64 | 75 | | V _{GS} =2.5V, I _D = 3.1A |
| | | P-channel | — | 89 | 100 | | V _{GS} =-3.5V, I _D = -2A |
| V _{GS(th)} | Gate threshold voltage | N-channel | 0.4 | 0.72 | 1 | V | V _{DS} = V _{GS} , I _D = 250μA |
| | | P-channel | 0.4 | 0.56 | 1 | | T _J = 125°C |
| | | N-channel | -0.4 | -0.78 | -1 | | V _{DS} = V _{GS} , I _D = -250μA |
| | | P-channel | -0.4 | -0.66 | -1 | | T _J = 125°C |
| I _{DSS} | Drain-to-Source leakage current | N-channel | — | — | 1 | μA | V _{DS} = 20V, V _{GS} = 0V |
| | | P-channel | — | — | -1 | | V _{DS} = -20V, V _{GS} = 0V |
| I _{GSS} | Gate-to-Source forward leakage | N-channel | — | — | 100 | nA | V _{GS} = 8V |
| | | N-channel | — | — | -100 | | V _{GS} = -8V |
| | | P-channel | — | — | 100 | | V _{GS} = 8V |
| | | P-channel | — | — | -100 | | V _{GS} = -8V |
| C _{iss} | Input capacitance | N-channel | — | 348 | 420 | pF | V _{GS} = 0V, V _{DS} = 10V, f = 1.0MHz |
| C _{oss} | Output capacitance | N-channel | — | 58 | 70 | | |
| C _{rss} | Reverse transfer capacitance | N-channel | — | 32 | 39 | | |
| C _{iss} | Input capacitance | P-channel | — | 519 | 622 | | V _{GS} = 0V, V _{DS} = -10V, f = 1.0MHz |
| C _{oss} | Output capacitance | P-channel | — | 75 | 90 | | |
| C _{rss} | Reverse transfer capacitance | P-channel | — | 58 | 70 | | |

Source-Drain Ratings and Characteristics

| Symbol | Parameter | | Min. | Typ. | Max. | Units | Conditions |
|-----------------|--|-----------|------|------|------|-------|--|
| I _S | Continuous Source Current (Body Diode) | N-channel | — | — | 4.8 | A | MOSFET symbol showing the integral reverse p-n junction diode. |
| | | P-channel | — | — | -2.9 | | |
| I _{SM} | Pulsed Source Current (Body Diode) | N-channel | — | — | 17 | A | |
| | | P-channel | — | — | -11 | | |
| V _{SD} | Diode Forward | N-channel | — | 0.69 | 1.2 | V | I _S =0.94A, V _{GS} =0V |



SSF2145CH6

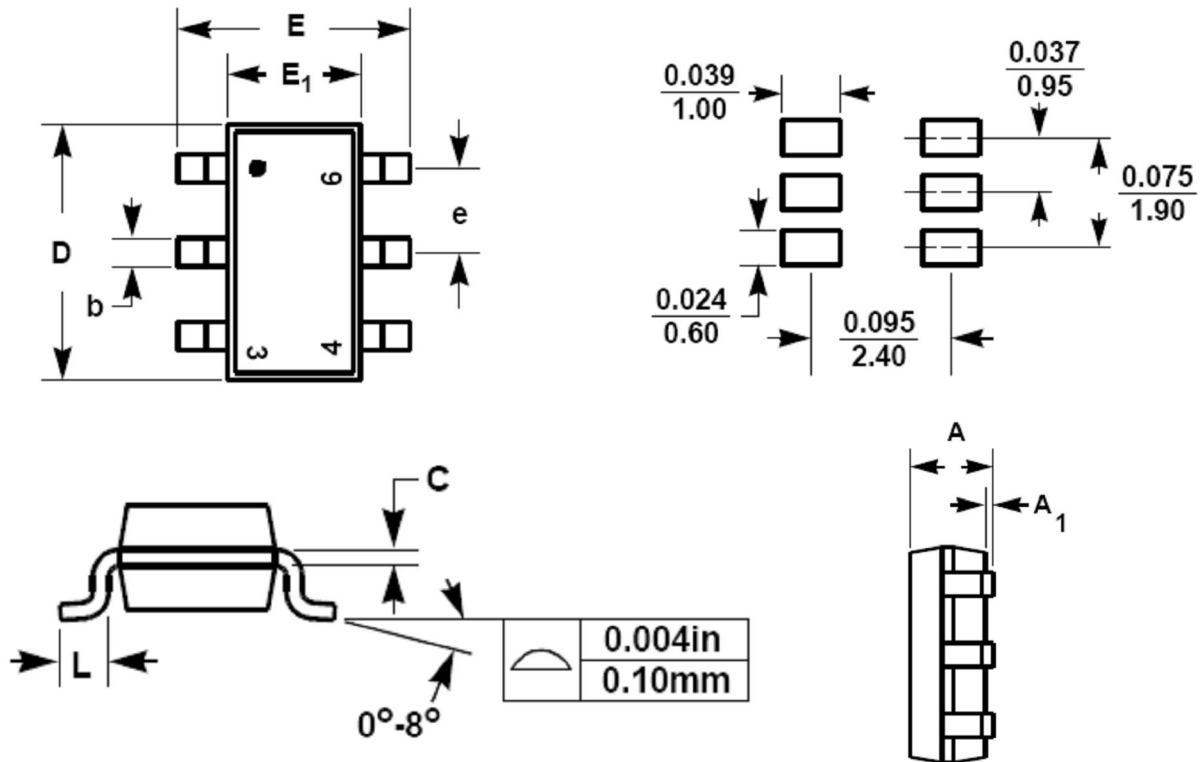
20V Complementary MOSFET

| | | | | | | | |
|--|---------|-----------|---|-------|------|--|-----------------------------|
| | Voltage | P-channel | — | -0.72 | -1.2 | | $I_S = -0.75A, V_{GS} = 0V$ |
|--|---------|-----------|---|-------|------|--|-----------------------------|

Notes:

- ① The maximum current rating is limited by bond-wires.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-ambient thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ C$

Mechanical Data



| SYMBOL | Millimeters | |
|--------|-------------|------|
| | MIN | MAX |
| A | 0.90 | 1.10 |
| A1 | 0.10 | |
| b | 0.30 | 0.50 |
| c | 0.08 | 0.20 |
| D | 2.70 | 3.10 |
| E | 2.60 | 3.00 |
| E1 | 1.40 | 1.80 |
| e | 0.95 BSC | |
| L | 0.35 | 0.55 |

Notes:

- ① Dimensions are inclusive of plating
- ② Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils
- ③ Dimension L is measured in gauge plane.
- ④ Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



Ordering and Marking Information

Device Marking: 2145C

Package (Available)
TSOP-6
Operating Temperature Range
C : -55 to 150 °C

Devices per Unit

| Package Type | Units/ Tube | Tubes/ Inner Box | Units/ Inner Box | Inner Boxes/ Carton Box | Units/ Carton Box |
|--------------|-------------|------------------|------------------|-------------------------|-------------------|
| TSOP-6 | 3000pcs | 10pcs | 30000pcs | 4pcs | 120000pcs |

Reliability Test Program

| Test Item | Conditions | Duration | Sample Size |
|-------------------------------------|---|--------------------------------------|---------------------|
| High Temperature Reverse Bias(HTRB) | $T_j=125^{\circ}\text{C}$ or 150°C @ 80% of Max $V_{DSS}/V_{CES}/V_R$ | 168 hours 500 hours 1000 hours | 3 lots x 77 devices |
| High Temperature Gate Bias(HTGB) | $T_j=125^{\circ}\text{C}$ or 150°C @ 100% of Max V_{GSS} | 168 hours 500 hours 1000 hours | 3 lots x 77 devices |